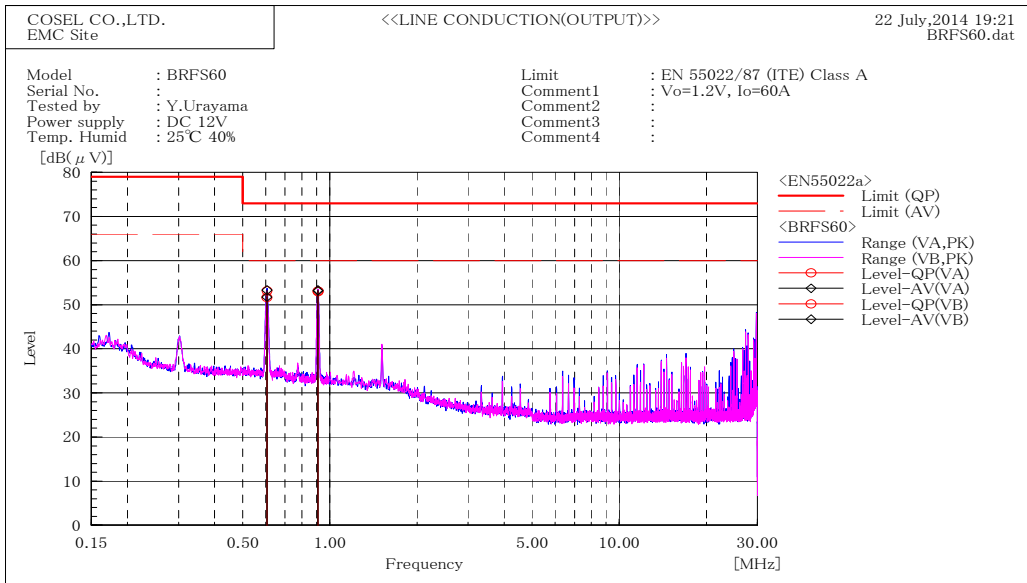
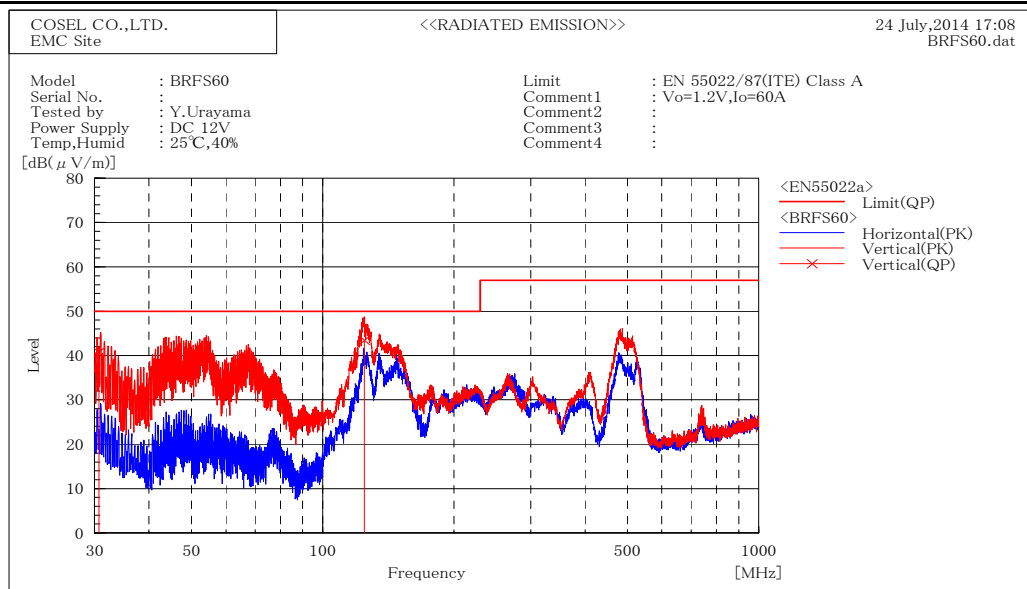


DATA SHEET		Date	24-Aug-14
Model	BRFS60	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	Y.Urayama



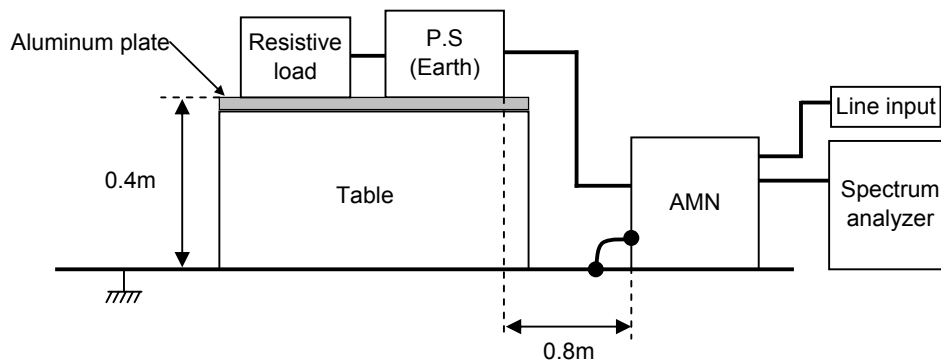
Frequency MHz	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
		QP	AV		QP	AV	QP	AV	QP	AV		
0.60557	VB	31.5	31.6	20.1	51.6	51.7	73	60	21.4	8.3	Pass	
0.60627	VA	33	33.2	20.1	53.1	53.3	73	60	19.9	6.7	Pass	
0.91037	VA	33	33.2	20.1	53.1	53.3	73	60	19.9	6.7	Pass	
0.91027	VB	32.8	33.1	20.1	52.9	53.2	73	60	20.1	6.8	Pass	



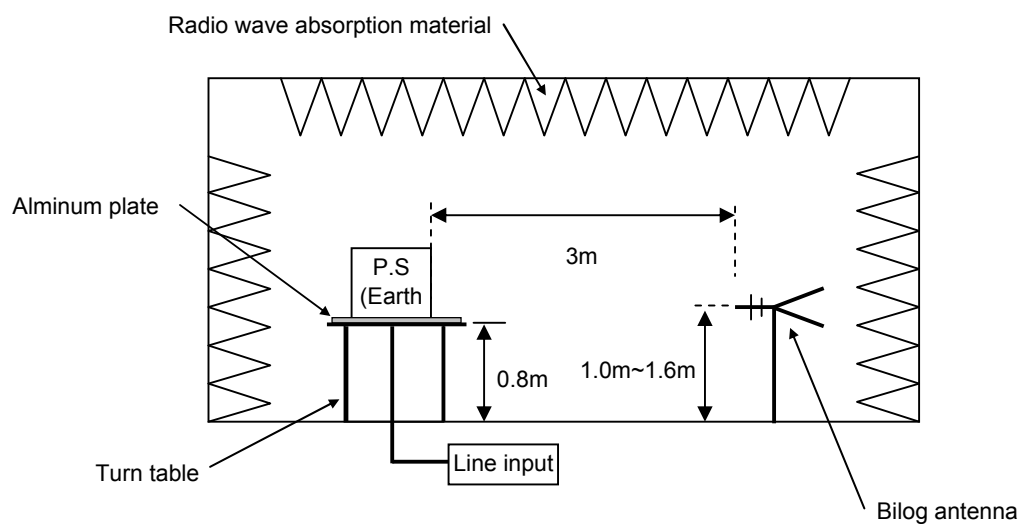
Frequency MHz	Polarization	Stability	Reading dB(μV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP		QP	QP					
30.68	V	Stable	54.4	-13.7	40.7	50	9.3	Pass	103	0	
124.696	V	Stable	60.6	-17.2	43.4	50	6.6	Pass	106	18	

DATA SHEET		Date	24-Aug-14
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	Y.Urayama

1. Line conduction



2. Radiated emission

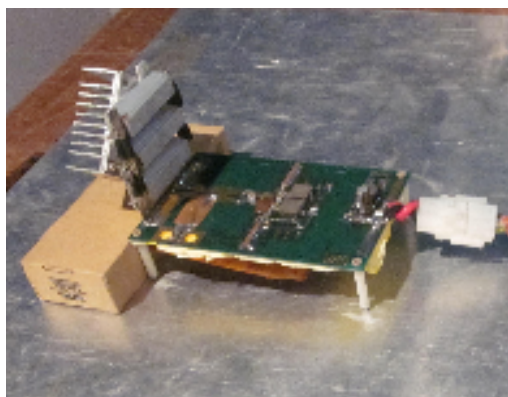


Conditions

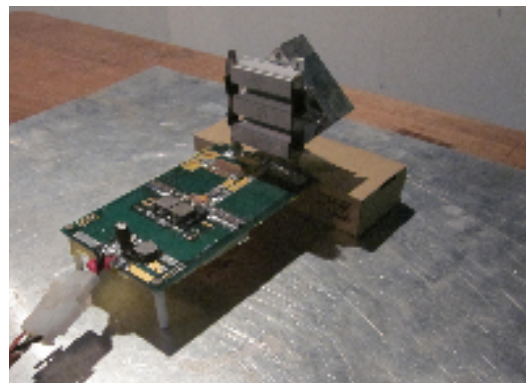
Test : EMI
Model Name : BRFS60

○Photographs of Test Set-Up

LINE CONDUCTION

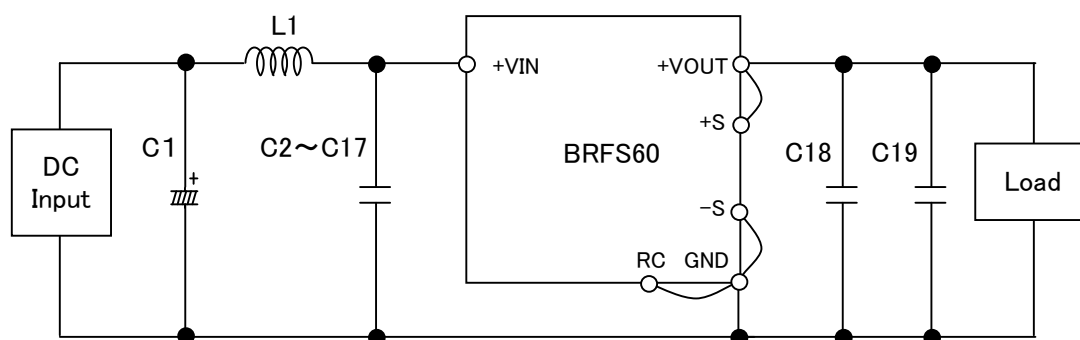


RADIATED EMISSION



○Testing circuitry

○Test Circuit



C1	: 25V	470 μ F	Electrolytic capacitor
C2~C17	: 16V	22 μ F	Ceramic capacitor
C18 ,C19	: 6.3V	100 μ F	Ceramic capacitor
L1	: 0.3 μ H	ETQP2H0R3BFA	(Panasonic Electronics Devices)